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Application/Control No.	Applicant(s)/Patent under Reexamination
10/553,684	YATABE, FUMIO
Examiner	Art Unit
Hai H. Huynh	3747

	SEAR	CHED	
Class	Subclass	Date	Examiner
123	399	8/10/2006	ннн
123	299	8/10/2006	ннн
123	300	8/10/2006	ннн
123	305	8/10/2006	ннн
123	494	8/10/2006	ннн
73	118.2	8/10/2006	ннн
update	search	1/17/2007	ннн

TERFERENCE SEARCHED		
Subclass	Date	Examiner
	1	<u> </u>

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East	8/10/2006	ннн
	1/17/2007	ннн